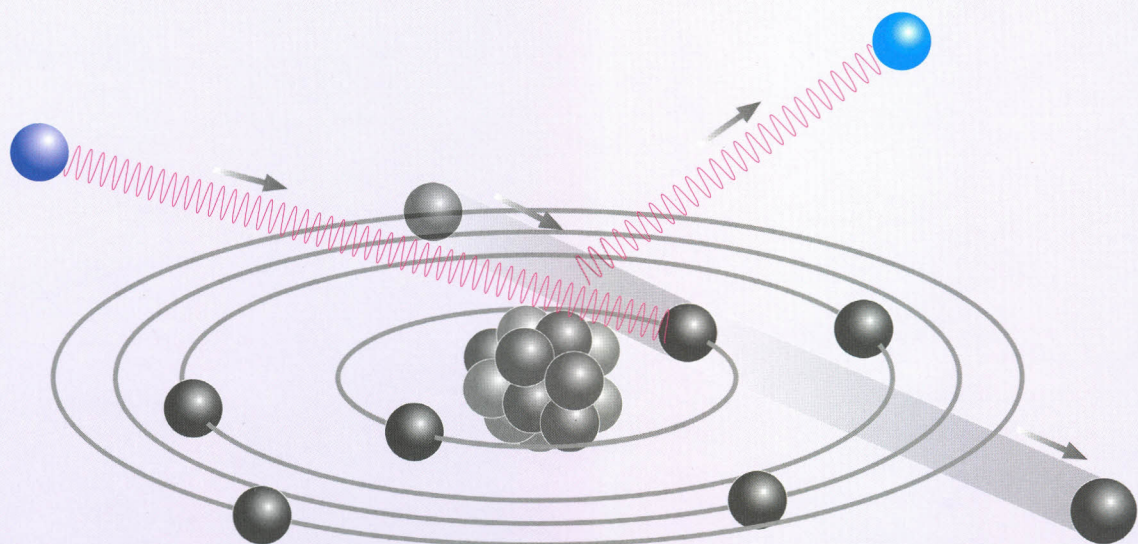


Understanding **XRF** *Spectrometry*

A practical guide
with worked
examples

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Volume

Basic concepts
and
instrumentation

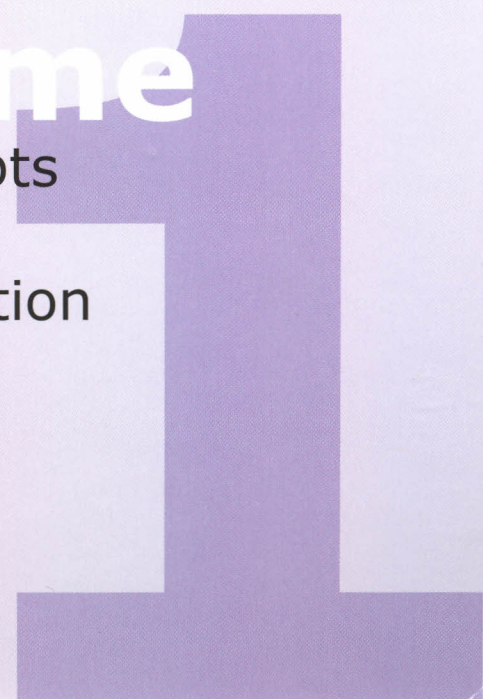


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